

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/764,569	MOTOYAMA ET AL.	
Examiner		Art Unit		Page 1 of 1
HIEU T. HOANG		2152		

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0221026	11-2004	Dorland, Chia-Chu S.	709/223
*	B	US-2004/0030768	02-2004	Krishnamoorthy et al.	709/223
*	C	US-7,069,480	06-2006	Lovy et al.	714/57
*	D	US-7,082,608	07-2006	Wilson et al.	719/315
*	E	US-6,636,981	10-2003	Barnett et al.	714/4
*	F	US-7,316,022	01-2008	Nishio, Masahiro	719/321
*	G	US-5,504,921	04-1996	Dev et al.	709/223
*	H	US-2005/0086368	04-2005	Winter, Robert L.	709/239
*	I	US-6,539,425	03-2003	Stevens et al.	709/220
*	J	US-2002/0004828	01-2002	Davis et al.	709/223
*	K	US-2003/0097425	05-2003	Chen, Weihai	709/220
*	L	US-2004/0153536	08-2004	Strassner, John	709/223
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.